



**ALPHA & OMEGA**  
SEMICONDUCTOR



**AO4813**

**Dual P-Channel Enhancement Mode Field Effect Transistor**

### General Description

The AO4813 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , and low gate charge. This device is suitable for use as a load switch or in PWM applications. Standard product AO4813 is Pb-free (meets ROHS & Sony 259 specifications). AO4813L is a Green Product ordering option. AO4813 and AO4813L are electrically identical.

### Features

$V_{DS}$  (V) = -30V  
 $I_D$  = -7.1 A ( $V_{GS}$  = -10V)  
 $R_{DS(ON)} < 25m\Omega$  ( $V_{GS}$  = -10V)  
 $R_{DS(ON)} < 40m\Omega$  ( $V_{GS}$  = -4.5V)



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>A</sup>	$I_D$	-7.1	A
$T_A=70^\circ C$		-5.6	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	-30	
Power Dissipation <sup>A</sup>	$P_D$	2	W
$T_A=70^\circ C$		1.28	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	48	62.5	°C/W
Steady-State		74	110	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	35	40	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		-1	-5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			$\pm100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.4	-2	-2.7	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	-30			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-7.1\text{A}$ $T_J=125^\circ\text{C}$		20	25	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-5.6\text{A}$		27	33	
				29	40	
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-7.1\text{A}$		19.6		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.7	-1	V
$I_S$	Maximum Body-Diode Continuous Current				-4.2	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		1573		pF
$C_{\text{oss}}$	Output Capacitance			319		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			211		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		6.7		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge (10V)	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-7.1\text{A}$		30.9		nC
$Q_g(4.5\text{V})$	Total Gate Charge (4.5V)			16.1		nC
$Q_{\text{gs}}$	Gate Source Charge			8		nC
$Q_{\text{gd}}$	Gate Drain Charge			4.4		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=2.2\Omega, R_{\text{GEN}}=3\Omega$		9.5		ns
$t_r$	Turn-On Rise Time			8		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			44.2		ns
$t_f$	Turn-Off Fall Time			22.2		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=-7.1\text{A}, dI/dt=100\text{A}/\mu\text{s}$		25.5		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=-7.1\text{A}, dI/dt=100\text{A}/\mu\text{s}$		14.7		nC

A: The value of  $R_{\text{QJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $\leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\text{QJA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{QJL}}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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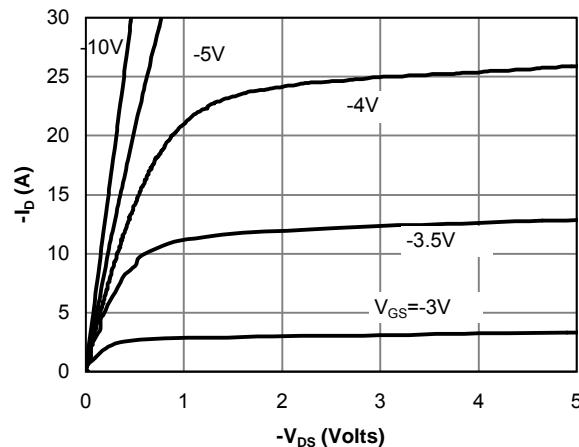
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL**


Fig 1: On-Region Characteristics

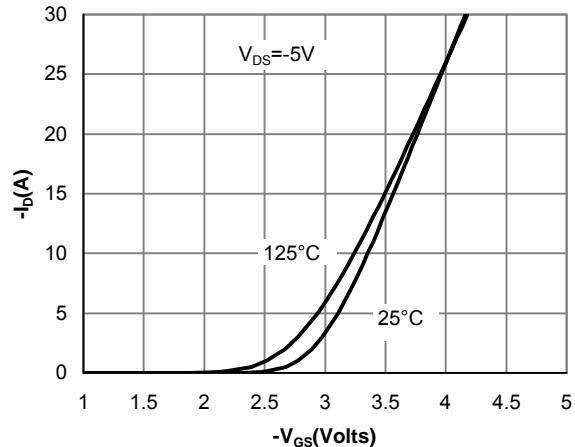


Figure 2: Transfer Characteristics

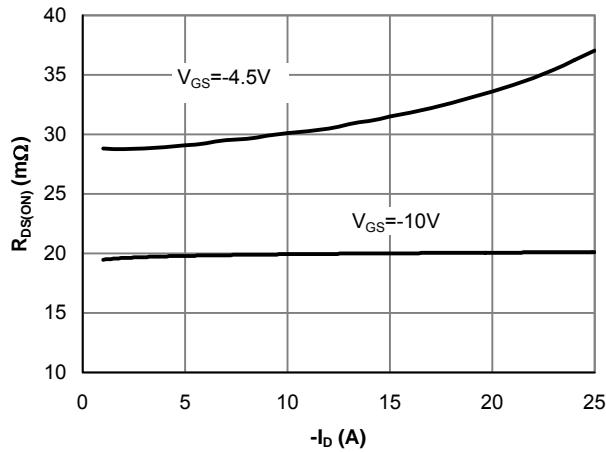


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

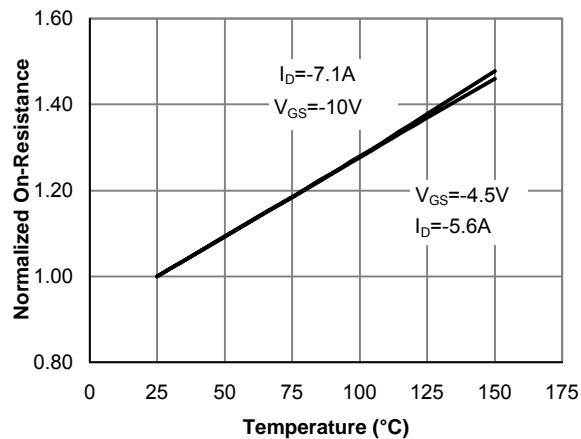


Figure 4: On-Resistance vs. Junction Temperature

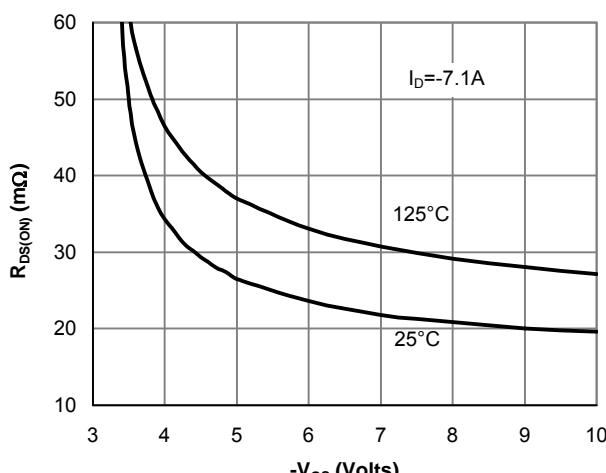


Figure 5: On-Resistance vs. Gate-Source Voltage

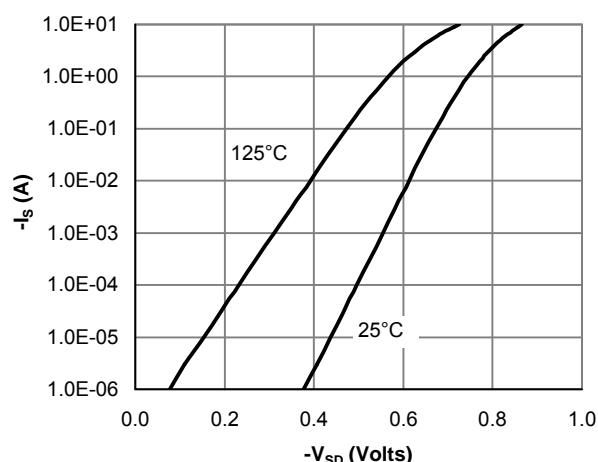


Figure 6: Body-Diode Characteristics

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL

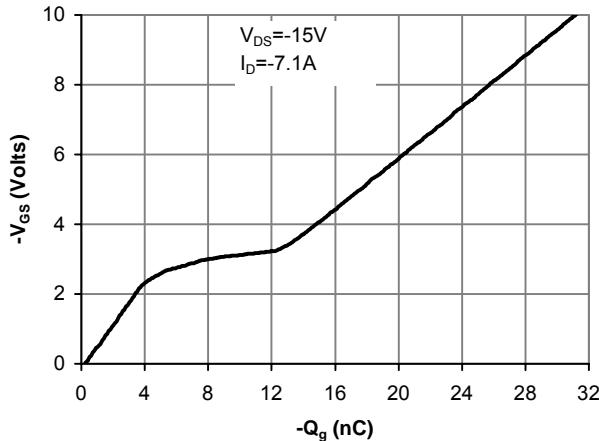


Figure 7: Gate-Charge Characteristics

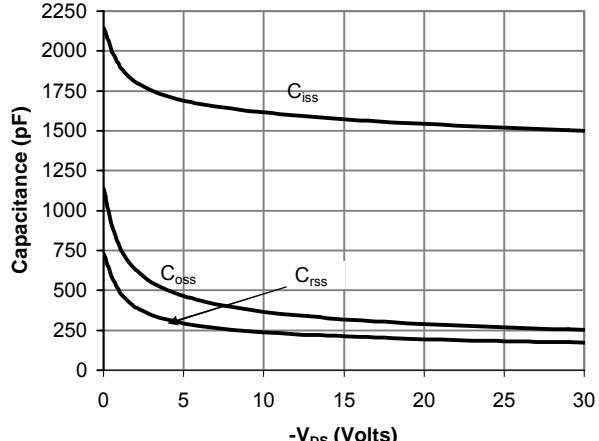


Figure 8: Capacitance Characteristics

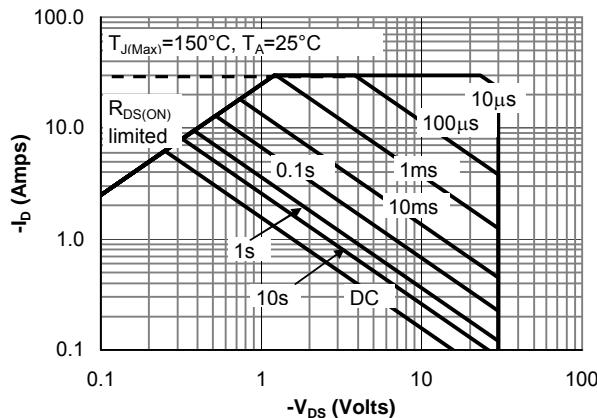


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

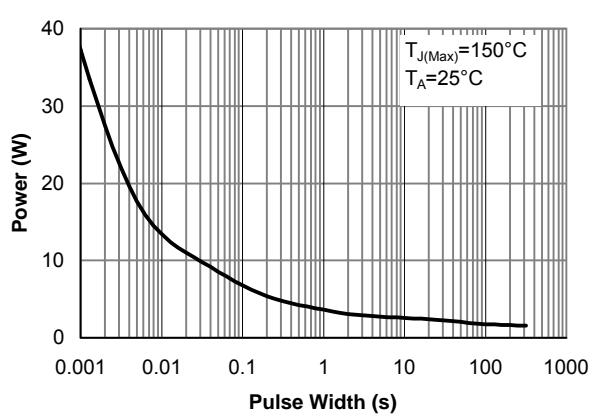


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

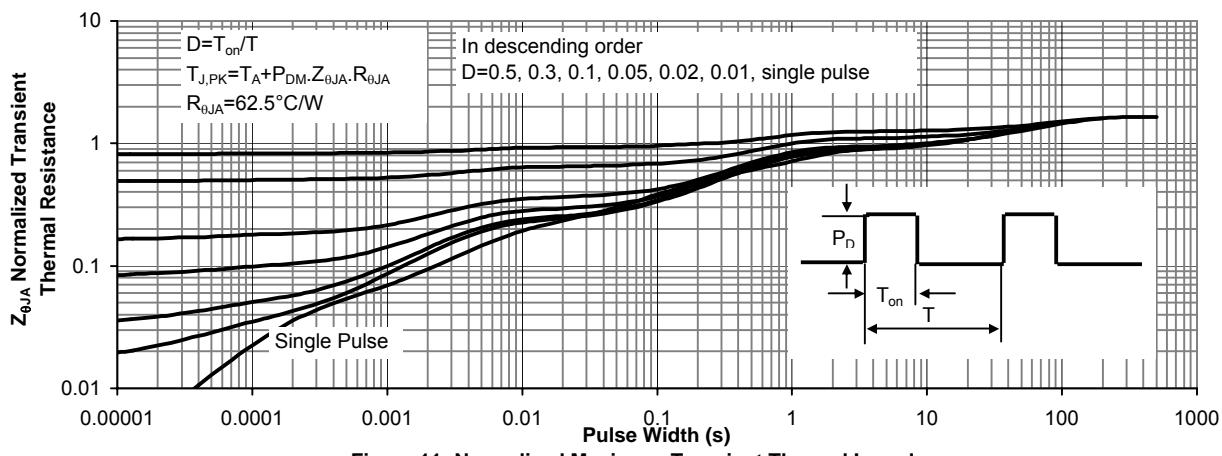


Figure 11: Normalized Maximum Transient Thermal Impedance